54F193

FEATURES

- Synchronous reversible 4-bit binary counting
- Asynchronous parallel load
- Asynchronous reset (clear)
- Expandable without external logic

DESCRIPTION

The 54F193 is a 4-bit synchronous up/ down counter in the binary mode. Separate up/down clocks, CP_U and CP_D respectively, simplify operation. The outputs change state synchronously with the Low-to-High transition of either Clock input. If the CP_U clock is pulsed while CP_D is held High, the device will count up ... if CP_D is

pulsed while CP_{U} is held High, the device will count down. Only one Clock input can be held High at any time, or erroneous operation will result. The device can be cleared at any time by the asynchronous reset pin – it may also be loaded in parallel by activating the asynchronous parallel load pin.

ORDERING INFORMATION

DESCRIPTION	ORDER CODE	PACKAGE DESIGNATOR*
16-Pin Ceramic DIP	54F193/BEA	GDIP1-T16
16-Pin Ceramic Flat Pack	54F193/BFA	GDFP2-F16
20-Pin Ceramic LLCC	54F193/B2A	CQCC2-N20

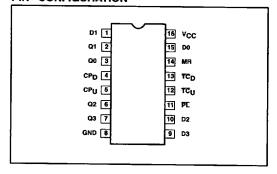
^{*} MIL-STD 1835 or Appendix A of 1995 Military Data Handbook

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

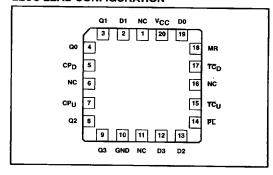
PINS	DESCRIPTION	54F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
CPU	Count up clock input (active rising edge)	1.0/2.0	20μA/1.2mA
CP _D	Count down clock input (active rising edge)	1.0/2.0	20μA/1.2mA
MR	Asynchronous master reset input (active High)	1.0/1.0	20μA/0.6mA
PL	Asynchronous parallel load input (active Low)	1.0/1.0	20μA/0.6mA
D0 - D3	Parallel data inputs	1.0/1.0	20μA/0.6mA
Q0 - Q3	Flip-flop outputs	50/33	1.0mA/20mA
TC _D	Terminal count down (borrow) output (active Low)	50/33	1.0mA/20mA
TC∪	Terminal count up (carry) output (active Low)	50/33	1.0mA/20mA

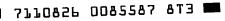
NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20μA in the High state and 0.6mA in the Low state.

PIN CONFIGURATION



LLCC LEAD CONFIGURATION





November 7, 1990

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FL DO D1 D2 D3 CPU TCD MR Q0 Q1 Q2 Q3 14 3 2 6 7

Inside the device are four master-slave JK flip-flops with the necessary steering logic to provide the asynchronous reset, load, and synchronous count up and count down functions.

Each flip-flop contains JK feedback from slave to master, such that a Low-to-High transition on the CP_D input will decrease the count by one, while a similar transition on the CP_U input will advance the count by one.

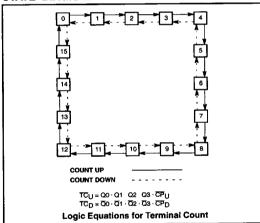
One clock should be held High while counting with the other, because the circuit will either count by twos or not at all, depending on the state of the first flip-flop, which cannot toggle as long as either Clock input is Low. Applications requiring reversible operation must make the reversing decision while the activating clock is High to avoid erroneous counts.

The Terminal Count Up (TC_D) and Terminal Count Down (TC_D) outputs are normally High. When the circuit has reached the maximum count state of 15, the next High-to-Low transition of CP_D will cause TC_D to go Low. TC_D will stay Low until CP_D goes High again, duplicating the count up clock, although delayed by two gate delays. Likewise, the TC_D output will go Low when the circuit is in the zero state and the CP_D goes Low. The TC outputs can be used as the Clock input signals to the next higher order circuit in a multistage counter, since they duplicate the clock waveforms. Multistage counters will not be fully synchronous, since there is a two- gate delay time difference added for each stage that is added.

The counter may be preset by the asynchronous parallel load capability of the circuit. Information present on the parallel Data inputs D0 - D3) is loaded into the counter and appears on the outputs regardless of the conditions of the Clock inputs when the

Parallel Load (PL) input is Low. A High level on the Master Reset (MR) in put will disable the parallel load gates, override both Clock inputs, and set all Q outputs Low. If one of the Clock inputs is Low during and after a reset or load operation, the next Low-to-High transition of that clock will be interpreted as a legitimate signal and will be counted.

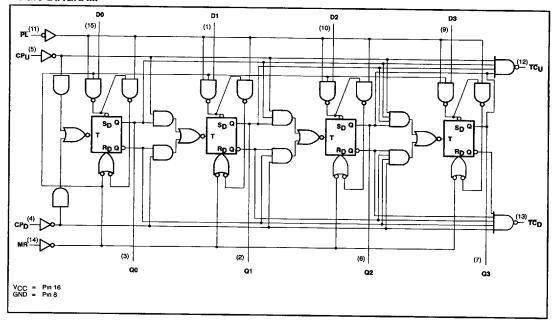
STATE DIAGRAM



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LOGIC DIAGRAM



MODE SELECT — FUNCTION TABLE

OPERATING		_		INP	UTS				OUTPUTS					
MODE	MR	PL	CPυ	CPD	DO	D1	D2	D3	Q0	Q1	Q2	Q3	TCU	TCD
Reset (clear)	H	X X	X	L	X X	X X	X X	X	L L	L	L L	L L	Н	L
Parallel load	L L L		X X L	L H X	H H	LLHH	LLHH	L H H	L H H	L H	L H	L L H	H H L	HHH
Count up	L	Н	1	H	Х	Х	Х	х		Cou	nt up		Н1	Н
Count down	L	Н	Н	1	Х	Х	х	Х			down		Н	H ²

High voltage levelLow voltage level

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X = Don't care

⁼ Low-to-High clock transition

54F193

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage range	-0.5 to +7.0	V
V _i	Input voltage range	-0.5 to +7.0	V
h	Input current range	-30 to +5.0	mA
V _O	Voltage applied to output in High output state range	-0.5 to +V _{CC}	٧
lo	Current applied to output in Low output state	40	mA
T _{STG}	Storage temperature range	-65 to +150	∘c

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		LIMITS					
		MIN	NOM	MAX				
V _{CC}	Supply voltage	4.5	5.0	5.5	٧			
VIH	High-level input voltage	2.0	I		V			
V _{IL}	Low-level input voltage			0.8	٧			
l _{iK}	Input clamp current			-18	mA			
ГОН	High-level output current			-1	mA			
loL	Low-level output current			20	mA			
TA	Operating free-air temperature range	-55		+125	°C			

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	PARAMETER TEST CONDITIONS ³				LIMITS				
				MIN	TYP ⁴	MAX				
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = MAX, I _{OH} =	MAX, V _{IH} = MIN	2.5			٧			
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX, I _{OL} :		.35	.5	٧				
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I =		-0.73	-1.2					
I _{IH2}	Input current at maximum input voltage	V _{CC} = MAX, V _I = 7.0V				100	μА			
l _{IH1}	High-level input current	V _{CC} = MAX, V _I =	: 2.7V		1	20	μA			
I _{IL}	Low-level input current	V _{CC} = MAX, V _I = 0.5V	CP _U , CP _D			-1.8	mA			
-16	•		Other inputs		-0.4	-0.6	mA			
los	Short-circuit output current ⁵	V _{CC} = MAX		-60		-150	mA			
loc	Supply current ⁶ (total)	V _{CC} = MAX	(32	50	mA			

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54F193

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS			LIMIT	rs		UNIT	
			1 V	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50pF, R_L = 500\Omega$			$T_A = -55^{\circ}\text{C to } +125^{\circ}\text{C}$ $V_{CC} = +5.0V \pm 10\%$ $C_L = 50\text{pF}, R_L = 500\Omega$		
			MIN	TYP	MAX	MIN	MAX		
^f MAX	Maximum clock frequency	Waveform 1	100	125		90		MHz	
t _{PLH} t _{PHL}	Propagation delay CP _U or CP _D to TC _U or TC _D	Waveform 2	2.5 3.0	5.5 5.0	8.5 8.0	2.5 3.0	9.0 9.0	ns ns	
t _{PLH} t _{PHL}	Propagation delay CP _U or CP _D to Qn	Waveform 1	2.5 5.0	5.5 8.5	8.5 12.0	3.0 6.0	9.0 13.0	ns ns	
t _{PLH} t _{PHL}	Propagation delay D _n to Qn	Waveform 4	2.0 6.0	4.0 9.5	7.0 13.5	1.5 6.0	7.5 15.0	ns ns	
t _{PLH} t _{PHL}	Propagation delay PE to Qn	Waveform 3	4.5 5.5	6.5 8.5	10.0 12.0	4.0 5.0	11.0 13.0	ns ns	
t _{PHL}	Propagation delay MR to Qn	Waveform 5	5.0	7.5	11.0	5.5	12.5	ns	
t _{PLH}	Propagation delay MR to TC _U	Waveform 5	6.0	8.5	12.0	5.5	12.5	ns	
t _{PHL}	Propagation delay MR to TC _D	Waveform 5	5.0	7.5	11.0	5.0	11.0	ns	
t _{PLH} t _{PHL}	Propagation delay PL to TC _U or TC _D	Waveform 3	6.0 6.0	9.5 9.0	13.5 12.0	6.0 6.0	15.0 13.0	ns ns	
t _{PLH} t _{PHL}	Propagation delay Dn to TC _U or TC _D	Waveform 4	5.5 4.5	9.0 8.5	13.0 12.5	5.0 4.5	14.0 13.5	ns	

AC SETUP REQUIREMENTS

SYMBOL PARAMETER	PARAMETER	TEST CONDITIONS	LIMITS						
		C _L = !	r _A = +25°0 cc = +5.0 50pF, R _L =	C V = 500 Ω	T _A = -55°C V _{CC} = +5 C _L = 50pF,				
		MIN	TYP	MAX	MIN	MAX			
t _s (H) t _s (L)	Setup time, High or Low Dn to PL	Waveform 6	4.5 4.5			5.0 5.0		ns ns	
t _h (H) t _h (L)	Hold time, High or Low On to PL	Waveform 6	2.0 2.0			2.0 2.0		ns ns	
t _w (L) ⁵	PE Pulse width Low	Waveform 1	6.0	<u> </u>		6.0			
t _w (H) ⁵ t _w (L) ⁵	CP _U or CP _D Pulse width High or Low	Waveform 1	3.5 5.0			3.5 5.0		ns	
t _w (L) ⁵	CP _U or CP _D Pulse width Low (Change of direction)	Waveform 1	10.0			10.0		ns ns	
t _w (H) ⁵	MR Pulse width High	Waveform 5	6.0			6.0		ns	
t _{rec}	Recovery time, PE to CPu or CPD	Waveform 3	6.0		l	8.0		— IIS	
t _{rec}	Recovery time MR to CPU or CPD	Waveform 5	4.0			4.0		ns	

NOTES:

- 1. TCu = CPu at terminal count up (HHHH).
- 2. TC_D = CP_D at terminal count down (LLLL).
 3. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type
- 4. All typical values are at V_{CC} = 5V, T_A = 25°C.

 5. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold. techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, IOS tests should be performed last.
- 6. Measure I_{CCH} with parallel load and Master Reset inputs grounded, all other inputs at 4.5V and all outputs open.
- Pulse width tests are guaranteed as specified, but are tested at 7.0ns due to tester limitations.

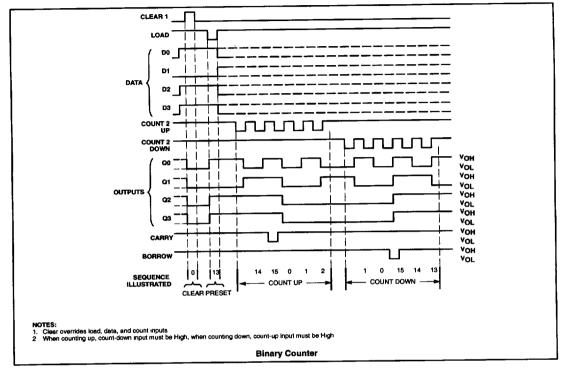
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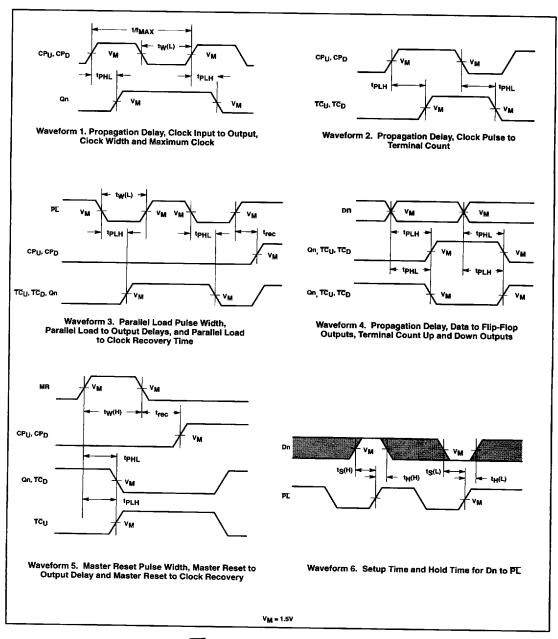
54F193

FUNCTIONAL WAVEFORM (Typical clear, load, and count sequences)



54F193

AC WAVEFORMS



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generators. Unclocked pins must be held at: ≤0.8V; ≥2.7V or open per

54F193

TEST CIRCUIT AND WAVEFORMS

FunctionTable.

